Search Notes			
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Application/Control No.
09/840,861
Examiner

Applicant(s)/Pate Reexamination	ent under
DUPRET ET AL	
Art Unit	

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Young J. Kim

SEARCHED			
Class	Subclass	Date	Examiner
435	6	4/13/2005	YJK
	91.1	4/13/2005	YJK
	91.2	4/13/2005	YJK

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	4/13/2005	YJK
STN Commercial Databases - see the search strategy for a list of databases searched.	4/13/2005	YJK
See enclosed for search strategy for Patent Database search	4/13/2005	YJK
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